

Special Issue

Application of Terahertz Imaging to Nondestructive Evaluation

Message from the Guest Editor

Dear Colleague, Terahertz technology shows great promise for the nondestructive evaluation of a variety of materials. This Special Issue focuses on all innovations that can improve nondestructive evaluation based on far- and near-field THz imaging as well as on the identification of THz spectroscopic fingerprints. We look forward, in particular, to investigations of new materials and samples and to improvements in resolution, penetration depth, measurement speed, and in the compactness of THz systems. The advances can rely on developments in devices (emitters, sensors), system design, or data processing methods. Keywords

- THz imaging
- THz spectroscopy
- Nondestructive Evaluation
- Signal Processing
- Image Processing

Guest Editor

Dr. Alexandre Locquet

Unité Mixte Internationale 2958 GeorgiaTech-CNRS, Georgia Tech
Lorraine, Metz, France

Deadline for manuscript submissions

closed (31 December 2022)



Sensors

an Open Access Journal
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Impact Factor 3.5
CiteScore 8.2
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Sensors
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
sensors@mdpi.com

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Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

Editor-in-Chief

Prof. Dr. Vittorio M. N. Passaro

Dipartimento di Ingegneria Elettrica e dell'Informazione (Department of Electrical and Information Engineering), Politecnico di Bari, Via Edoardo Orabona n. 4, 70125 Bari, Italy

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